

1 PAGE 1 OF 2 GROUP ART **ATTACHMENT** SERIAL NO. U.S. DEPARTMENT OF COMMERCE FORM PTO-892 TO PAPER NO. UNIT 6 PATENT AND TRADEMARK OFFICE 09/321,611 2133 APPLICANT(S) NOTICE OF REFERENCES CITED QU, DONGHUI **U.S. PATENT DOCUMENTS** FILING DATE SUB-CLASS CLASS NAME DOCUMENT NO. DATE 30 380 Matsuzaki et al. 3/1993 Α 5,199,070 708 650 Chung 9/2000 В 6,125,380 107 359 Boffi 8/2001 С 6,275,311 D Ε F G Н ١ J Κ FOREIGN PATENT DOCUMENTS SUB-CLASS **CLASS** NAME COUNTRY DATE DOCUMENT NO. Μ Ν 0 Ρ Q OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) Orton et al. (New fault tolerant techniques for residue number systems; IEEE, page(s): 1453 - 1464; Nov. R 1992) Stout (Basic Electrical Measurements; 2d Ed., 1960; pages 82-85.)

Т Nov. 1998) Gala et al. (A high speed VLSI algorithm for A*B modulo N; IEEE, page(s): 389 - 392 vol.1; 12-14 Aug. 1990) U DATE

Burgess (Efficient RNS to binary conversion using high-radix SRT division; IEEE; page(s): 1240 - 1243; 1-4

EXAMINER

GUY J. LAMARRE, P.E.

September 28, 2001

Form892ccs2106b

* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05(a).)



SERIAL NO. **GROUP ART ATTACHMENT** FORM PTO-892 U.S. DEPARTMENT OF COMMERCE UNIT TO PAPER NO. PATENT AND TRADEMARK OFFICE 6 09/321,611 2133 APPLICANT(S) NOTICE OF REFERENCES CITED QU, DONGHUI **U.S. PATENT DOCUMENTS** FILING DATE SUB-CLASS DATE **CLASS** DOCUMENT NO. NAME Α В C D Ε F G Н 1 J K FOREIGN PATENT DOCUMENTS SUB-CLASS DOCUMENT NO. DATE COUNTRY NAME **CLASS** L М Ν 0 Ρ Q OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) Bini et al. (Improved parallel polynomial division and its extensions; IEEE, page(s): 131 - 136; 24-27 Oct. 1992 Saha, A et al. (Design and FPGA implementation of efficient integer arithmetic algorithms; IEEE, page(s): 4 p; S 4-7 April 1993) Т **EXAMINER** DATE September 28, 2001 GUY J. LAMARRE, P.E. Form892ccs2106b

> * A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05(a).)

Jan. 5